

P01 LTE B7_QPSK20M_Rear Face_0cm_Ch20850_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 7	LTE-FDD, -	2510.000, 20850	6.49	1.83	37.4

Hardware Setup

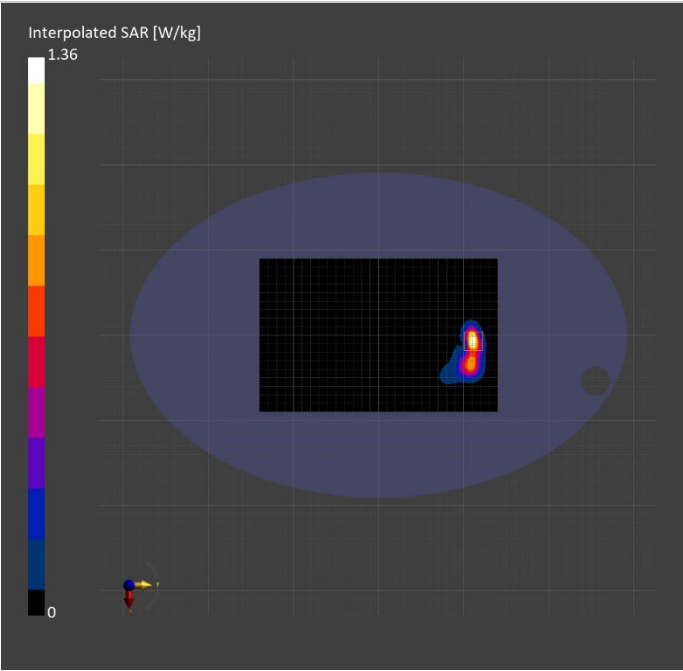
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2550-2026-06-19	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-19	2026-06-19
psSAR1g [W/kg]	0.966	1.04
psSAR10g [W/kg]	0.379	0.381
Power Drift [dB]	-0.04	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.2
Dist 3dB Peak [mm]		5.3



P02 LTE B12_QPSK10M_Top Side_0cm_Ch23130_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	Band 12	LTE-FDD, -	711.000, 23130	9.13	0.877	44.2

Hardware Setup

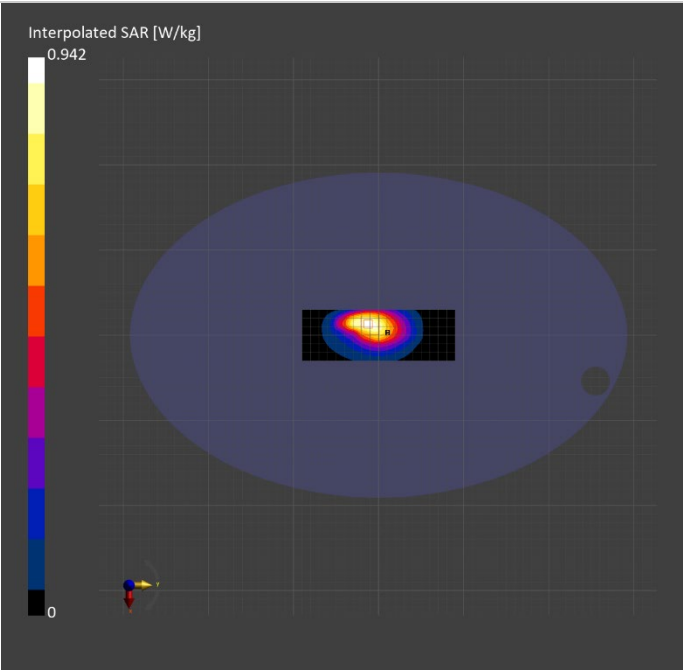
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL750-2026-05-22	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-22	2026-05-22
psSAR1g [W/kg]	0.805	0.872
psSAR10g [W/kg]	0.528	0.503
Power Drift [dB]	0.02	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.1
Dist 3dB Peak [mm]		9.7



P03 LTE B13_QPSK10M_Rear Face_0cm_Ch23230_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 13	LTE-FDD, -	782.000, 23230	9.13	0.903	43.8

Hardware Setup

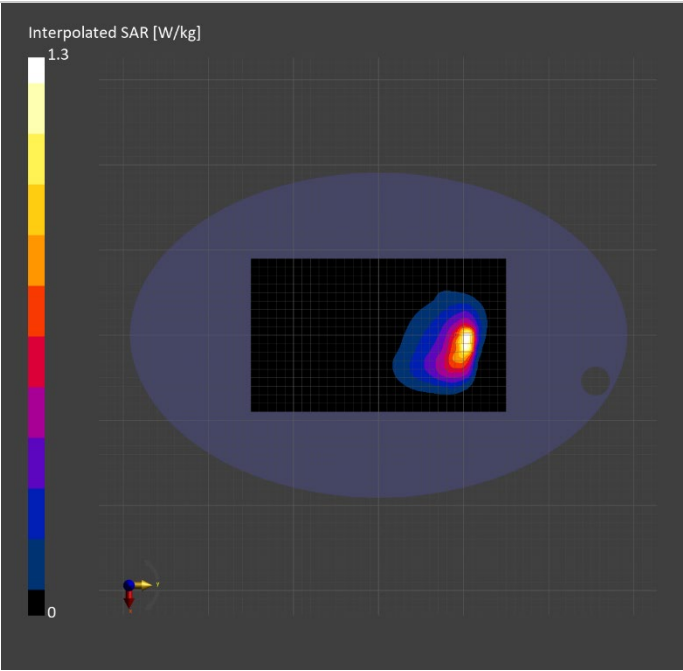
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL750-2026-05-22	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-22	2026-05-22
psSAR1g [W/kg]	1.08	1.09
psSAR10g [W/kg]	0.655	0.575
Power Drift [dB]	-0.00	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.2
Dist 3dB Peak [mm]		7.2



P04 LTE B14_QPSK10M_Rear Face_0cm_Ch23330_25RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 14	LTE-FDD, -	793.000, 23330	9.13	0.908	43.8

Hardware Setup

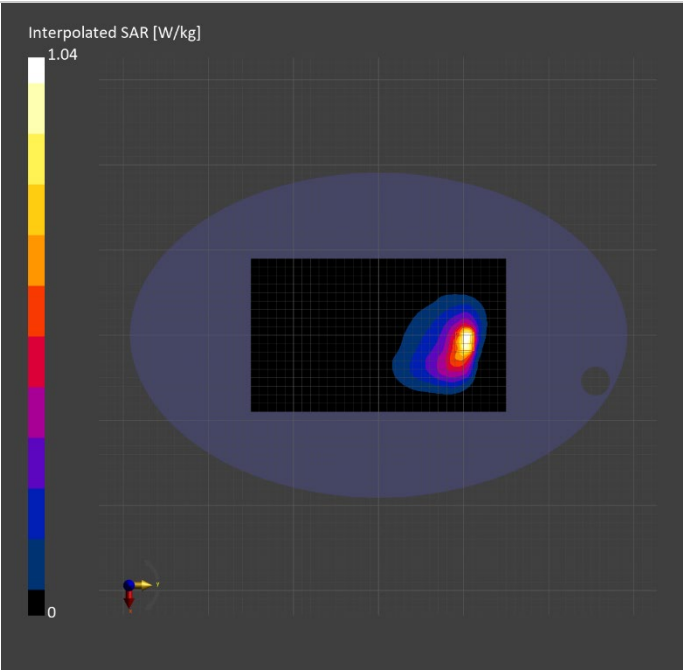
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL750-2026-05-22	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-22	2026-05-22
psSAR1g [W/kg]	0.862	0.879
psSAR10g [W/kg]	0.518	0.459
Power Drift [dB]	-0.00	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.6
Dist 3dB Peak [mm]		8.1



P05 LTE B19_QPSK15M_Rear Face_0cm_Ch24075_1RB_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 19	LTE-FDD, -	837.500, 24075	8.95	0.926	43.6

Hardware Setup

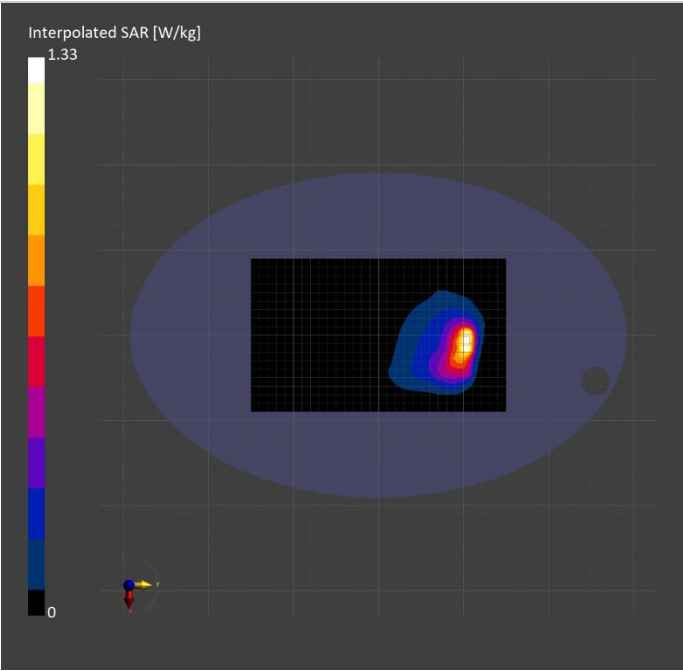
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL835-2026-05-23	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-23	2026-05-23
psSAR1g [W/kg]	1.11	1.13
psSAR10g [W/kg]	0.665	0.581
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.4
Dist 3dB Peak [mm]		8.1



P06 LTE B25_QPSK20M_Rear Face_0cm_Ch26140_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 25	LTE-FDD, -	1860.000, 26140	7.24	1.37	40.8

Hardware Setup

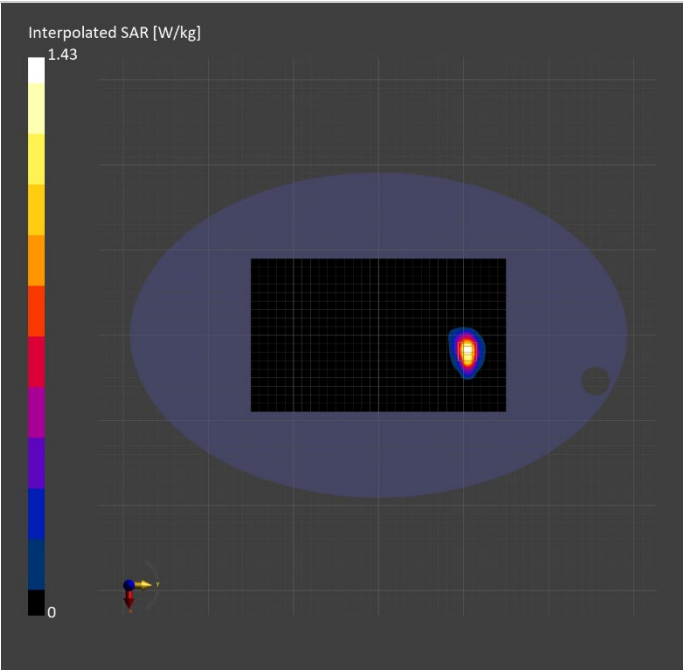
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL1950-2026-06-13	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-13	2026-06-13
psSAR1g [W/kg]	1.12	1.13
psSAR10g [W/kg]	0.561	0.561
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.5
Dist 3dB Peak [mm]		8.4



P07 LTE B26_QPSK15M_Rear Face_0cm_Ch26765_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 26	LTE-FDD, -	821.500, 26765	8.95	0.920	43.5

Hardware Setup

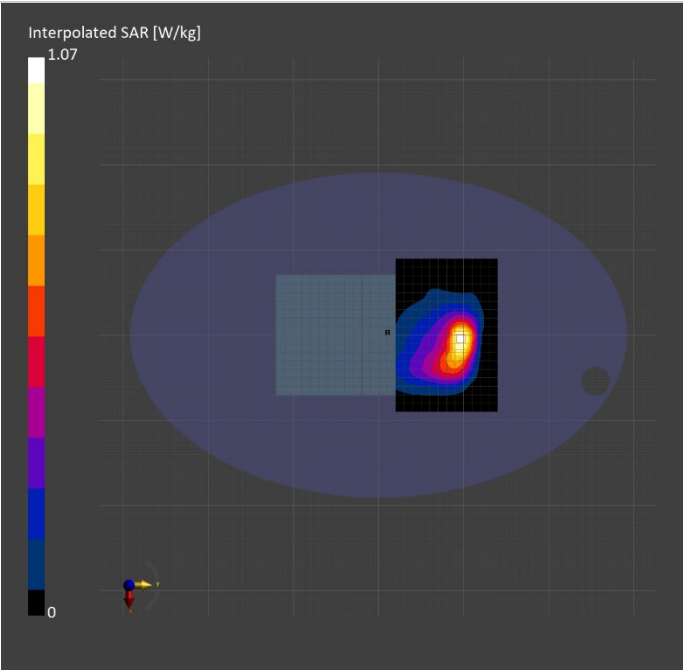
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL835-2026-05-23	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-23	2026-05-23
psSAR1g [W/kg]	0.919	1.06
psSAR10g [W/kg]	0.583	0.567
Power Drift [dB]	-0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.0
Dist 3dB Peak [mm]		7.2



P08 LTE B30_QPSK10M_Rear Face_0cm_Ch27710_1RB_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 30	LTE-FDD, -	2310.000, 27710	6.87	1.66	38.3

Hardware Setup

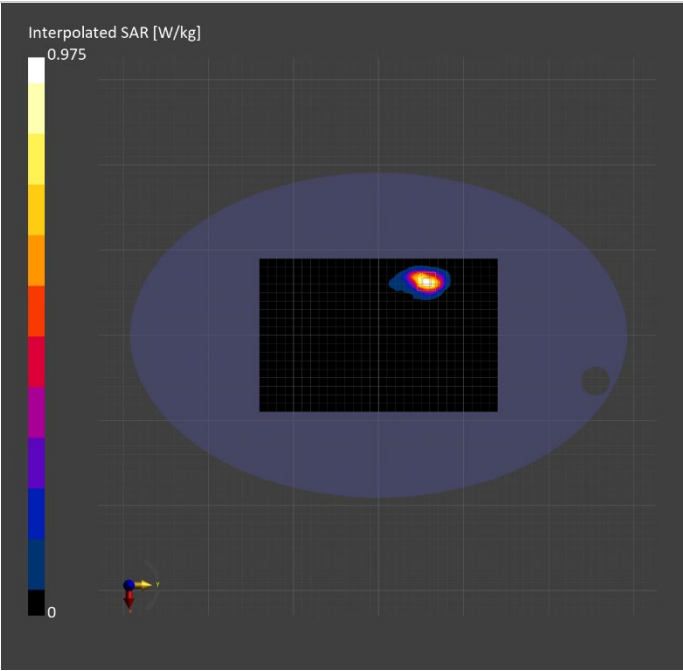
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2300-2026-06-15	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-15	2026-06-15
psSAR1g [W/kg]	0.750	0.766
psSAR10g [W/kg]	0.358	0.351
Power Drift [dB]	0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.1
Dist 3dB Peak [mm]		7.9



P09 LTE B38_QPSK20M_Rear Face_0cm_Ch38150_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 38	LTE-TDD, -	2610.000, 38150	6.49	1.90	37.2

Hardware Setup

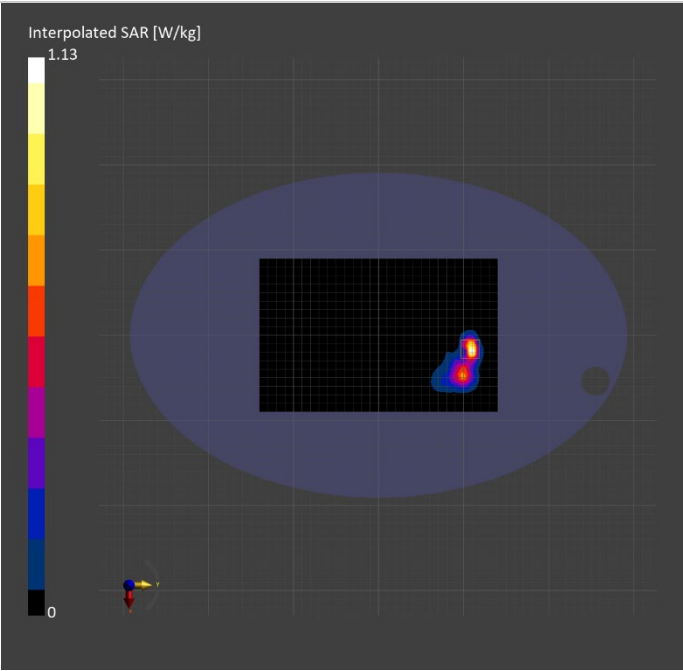
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2550-2026-06-20	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-20	2026-06-20
psSAR1g [W/kg]	0.756	0.888
psSAR10g [W/kg]	0.288	0.312
Power Drift [dB]	-0.02	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.2
Dist 3dB Peak [mm]		5.4



P10 LTE B41_QPSK20M_Top Side_0cm_Ch41490_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 0.00	Band 41	LTE-TDD, -	2680.000, 41490	6.49	2.11	39.0

Hardware Setup

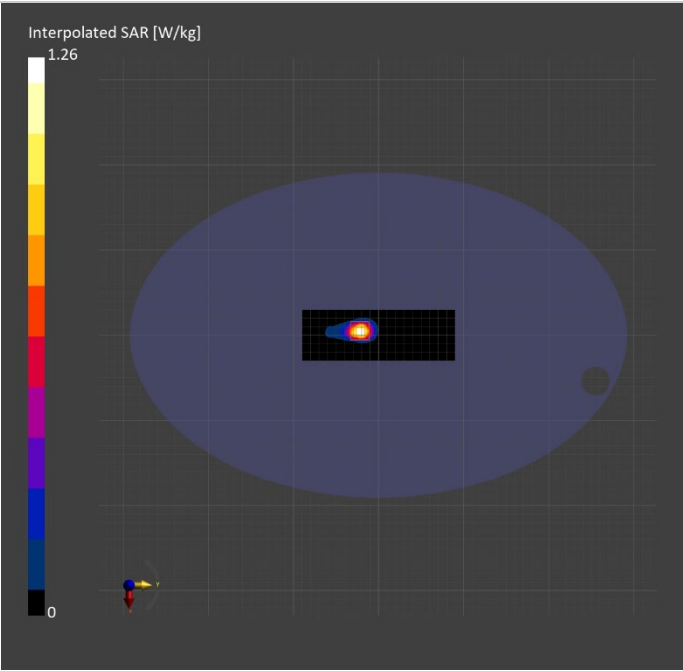
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2550-2026-06-20	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 180.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-20	2026-06-20
psSAR1g [W/kg]	0.967	1.05
psSAR10g [W/kg]	0.395	0.401
Power Drift [dB]	0.04	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.8
Dist 3dB Peak [mm]		7.1



P11 LTE B42_QPSK20M_Rear Face_0cm_Ch43340_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 42	LTE-TDD, -	3575.000, 43340	6.15	2.86	38.2

Hardware Setup

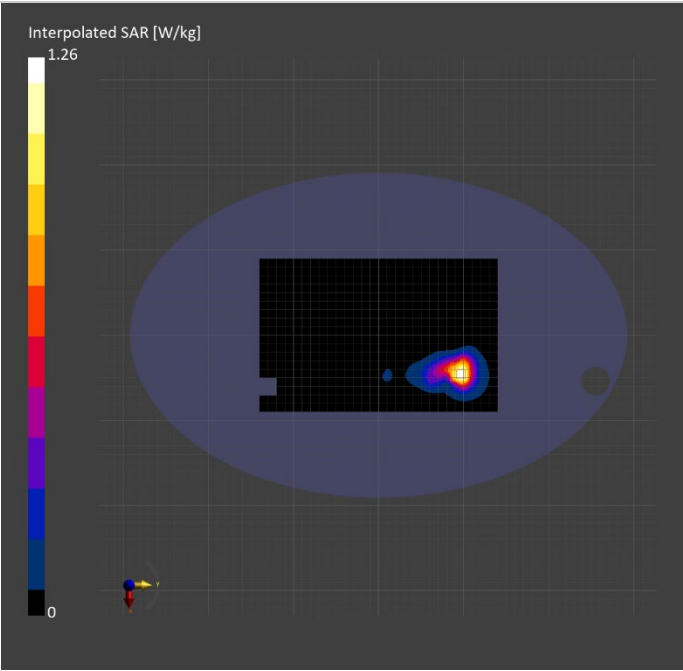
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL3500-2026-06-07	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-07	2026-06-07
psSAR1g [W/kg]	0.955	0.977
psSAR10g [W/kg]	0.426	0.423
Power Drift [dB]	0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.0
Dist 3dB Peak [mm]		8.5



P12 LTE B48_QPSK20M_Rear Face_0cm_Ch55340_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 48	LTE-TDD, -	3560.000, 55340	6.15	2.84	38.3

Hardware Setup

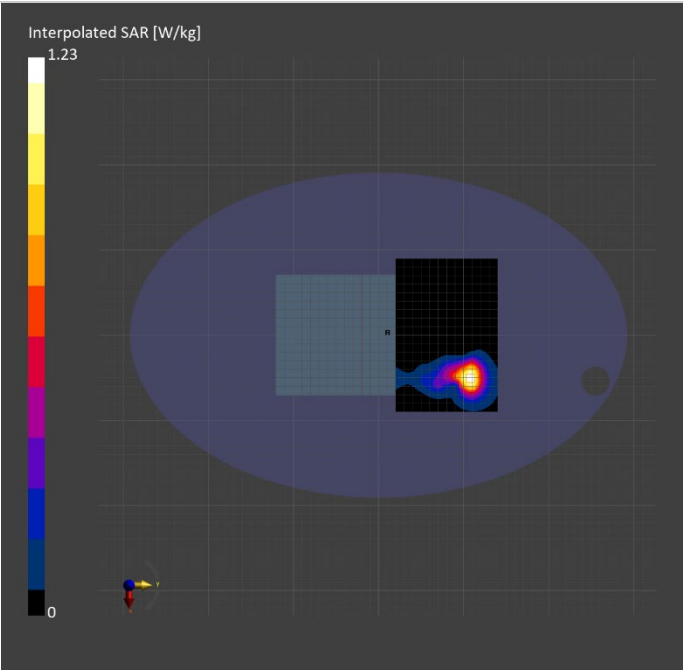
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL3500-2026-06-28	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-28	2026-06-28
psSAR1g [W/kg]	0.932	0.977
psSAR10g [W/kg]	0.426	0.439
Power Drift [dB]	0.00	0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		70.5
Dist 3dB Peak [mm]		11.5



P13 LTE B66_QPSK20M_Rear Face_0cm_Ch132322_1RB_OS50

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 66	LTE-FDD, -	1745.000, 132322	7.46	1.40	40.2

Hardware Setup

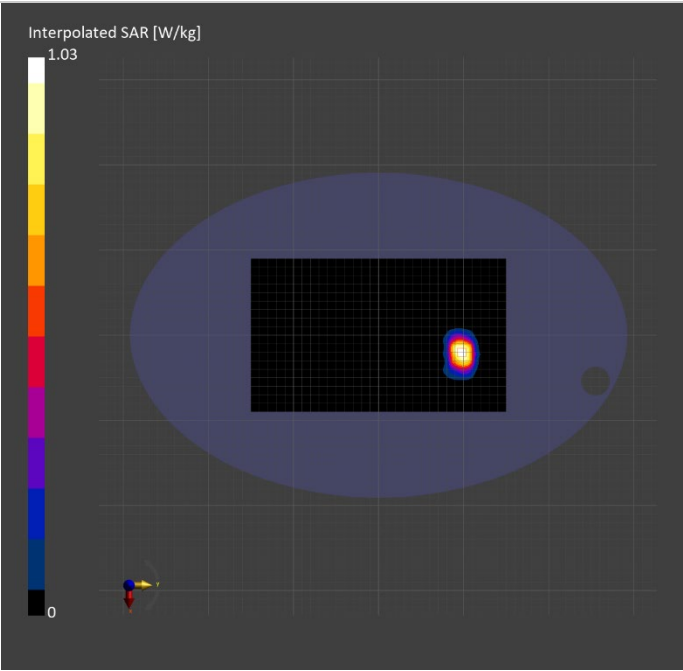
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL1750-2026-06-11	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-11	2026-06-11
psSAR1g [W/kg]	0.889	1.11
psSAR10g [W/kg]	0.489	0.537
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		8.4



P14 LTE B71_QPSK20M_Rear Face_0cm_Ch133222_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band 71	LTE-FDD, -	673.000, 133222	9.13	0.882	43.1

Hardware Setup

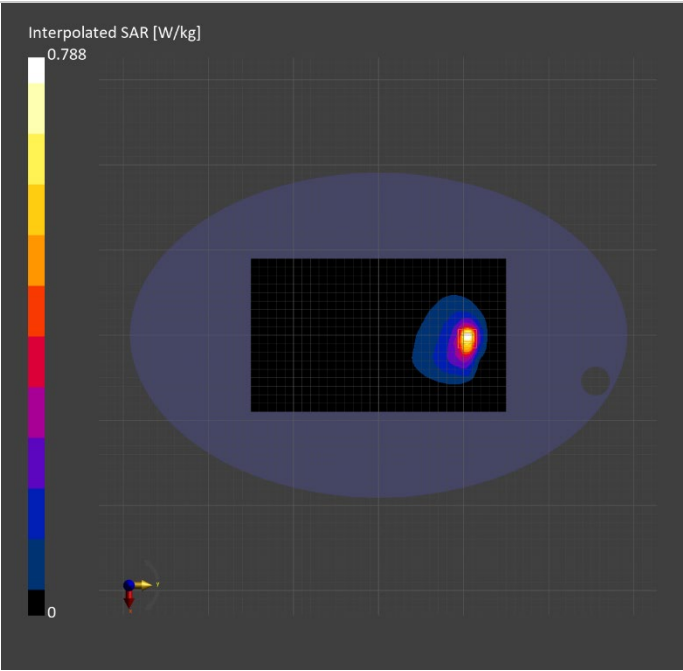
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL750-2026-05-22	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-22	2026-05-22
psSAR1g [W/kg]	0.623	0.634
psSAR10g [W/kg]	0.352	0.289
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.2
Dist 3dB Peak [mm]		8.1



P15 LTE B106_QPSK3M_Rear Face_0cm_Ch134322_1RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Custom Band	CW, -	899.000, 134322	8.85	0.930	42.0

Hardware Setup

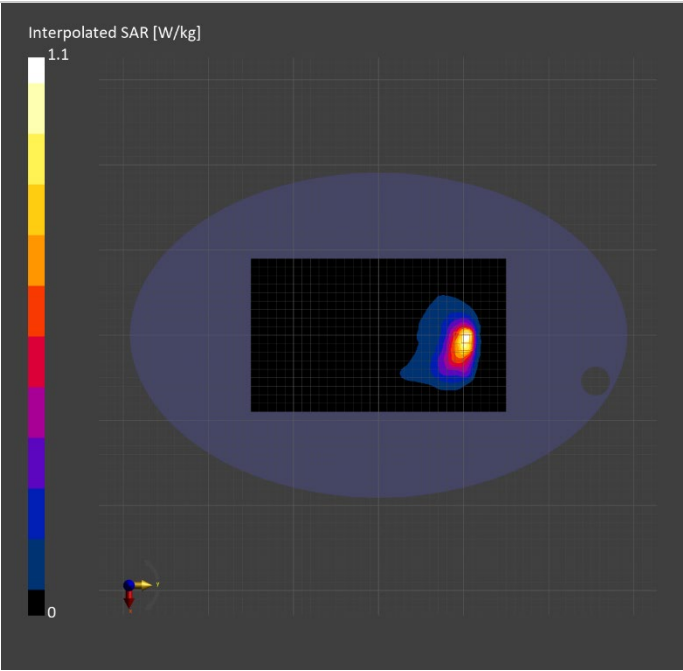
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL900-2026-05-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-24	2026-05-24
psSAR1g [W/kg]	0.898	1.00
psSAR10g [W/kg]	0.529	0.488
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		68.8
Dist 3dB Peak [mm]		8.4



P16 FR n5_QPSK20M_Rear Face_0cm_Ch166800_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n5	5G NR FR1 FDD, -	834.000, 166800	8.95	0.924	43.5

Hardware Setup

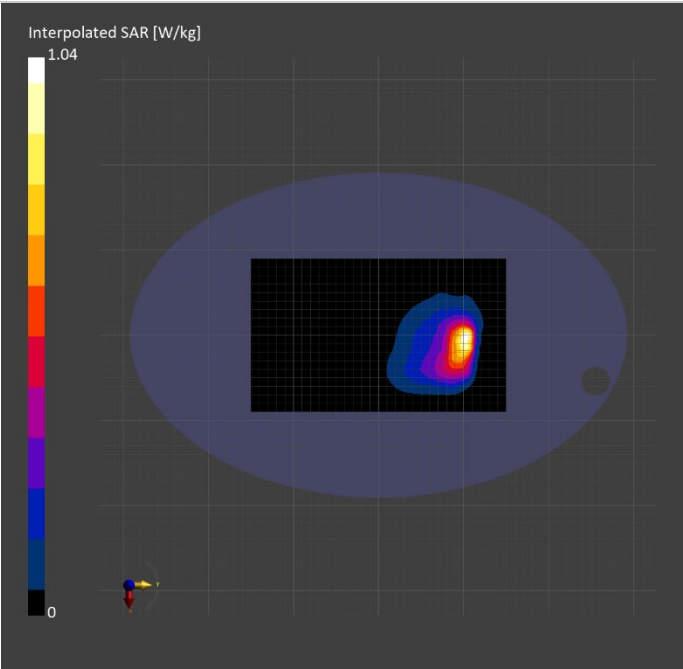
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL835-2026-05-23	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-23	2026-05-23
psSAR1g [W/kg]	0.873	0.937
psSAR10g [W/kg]	0.533	0.478
Power Drift [dB]	0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		66.2
Dist 3dB Peak [mm]		7.3



P17 FR n7_QPSK20M_Rear Face_0cm_Ch502000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n7	5G NR FR1 FDD, -	2510.000, 502000	6.49	1.83	37.4

Hardware Setup

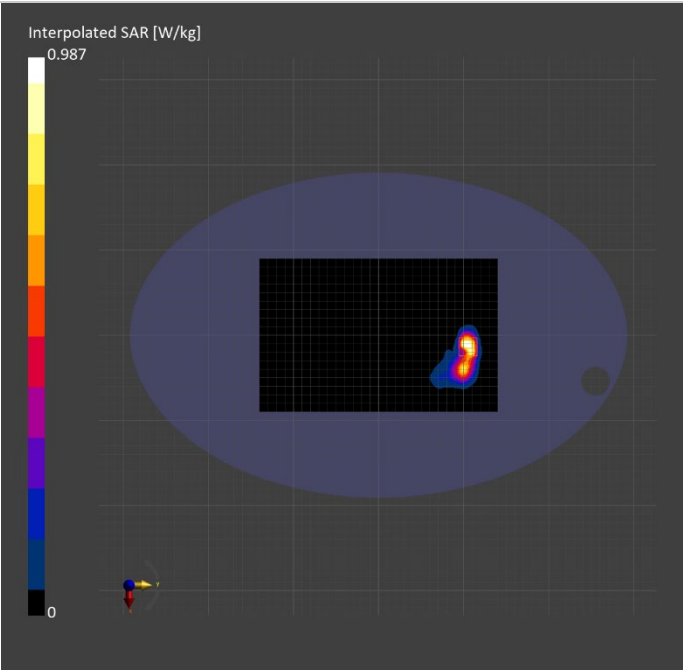
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2550-2026-06-19	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-19	2026-06-19
psSAR1g [W/kg]	0.764	0.917
psSAR10g [W/kg]	0.328	0.332
Power Drift [dB]	0.16	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.3
Dist 3dB Peak [mm]		5.4



P18 FR n25_QPSK20M_Rear Face_0cm_Ch381000_50RB_OS28

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n25	5G NR FR1 FDD, -	1905.000, 381000	7.24	1.40	40.9

Hardware Setup

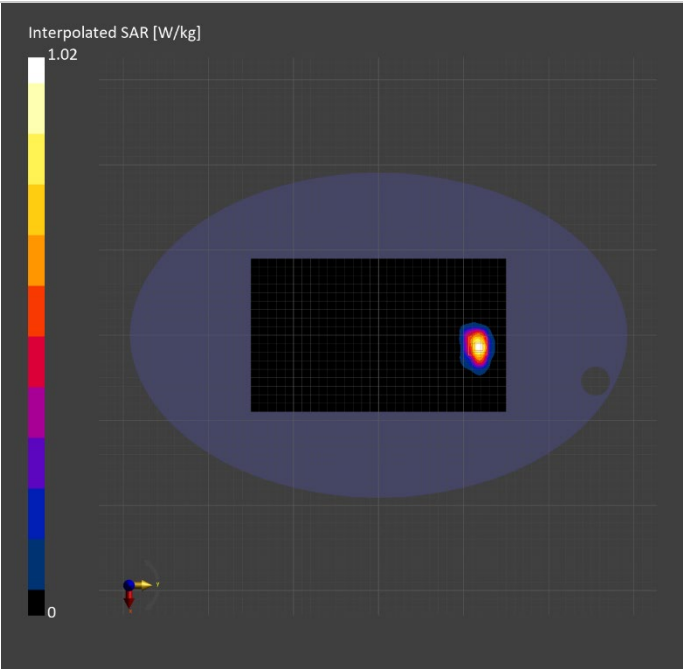
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL1950-2026-06-14	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-14	2026-06-14
psSAR1g [W/kg]	0.801	0.801
psSAR10g [W/kg]	0.408	0.398
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.9
Dist 3dB Peak [mm]		8.4



P19 FR n30_QPSK10M_Rear Face_0cm_Ch462000_25RB_OS14

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n30	5G NR FR1 FDD, -	2310.000, 462000	6.87	1.66	38.3

Hardware Setup

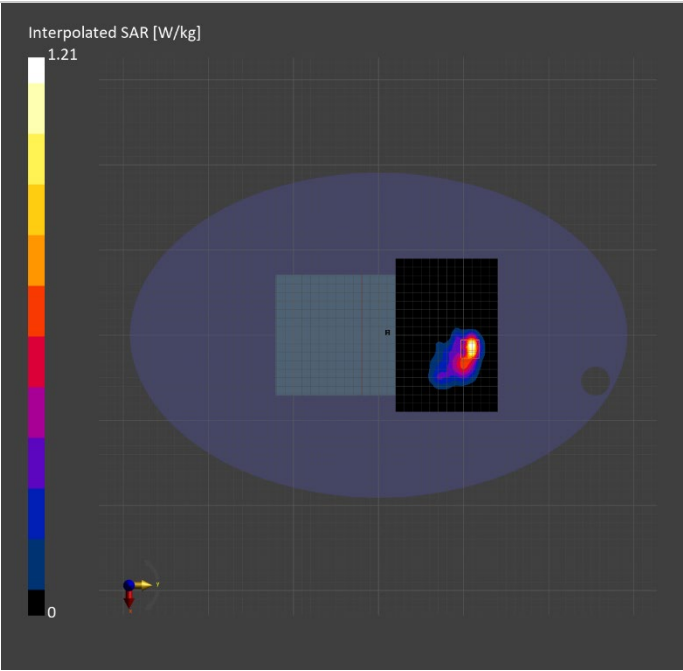
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2300-2026-06-15	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-15	2026-06-15
psSAR1g [W/kg]	0.862	0.890
psSAR10g [W/kg]	0.367	0.362
Power Drift [dB]	0.05	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.8
Dist 3dB Peak [mm]		6.4



P20 FR n41_QPSK100M_Rear Face_0cm_Ch509202_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n41	5G NR FR1 TDD, -	2546.010, 509202	6.49	1.85	37.3

Hardware Setup

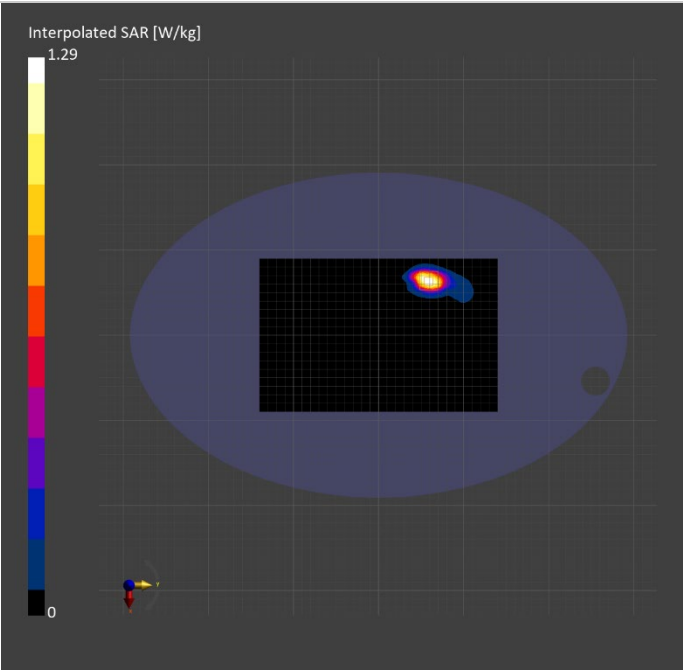
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2550-2026-06-21	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-21	2026-06-21
psSAR1g [W/kg]	1.01	1.06
psSAR10g [W/kg]	0.486	0.490
Power Drift [dB]	-0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.8
Dist 3dB Peak [mm]		7.9



P21 FR n48_QPSK40M_Rear Face_0cm_Ch638000_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n48	5G NR FR1 TDD, -	3569.995, 638000	6.15	2.85	38.2

Hardware Setup

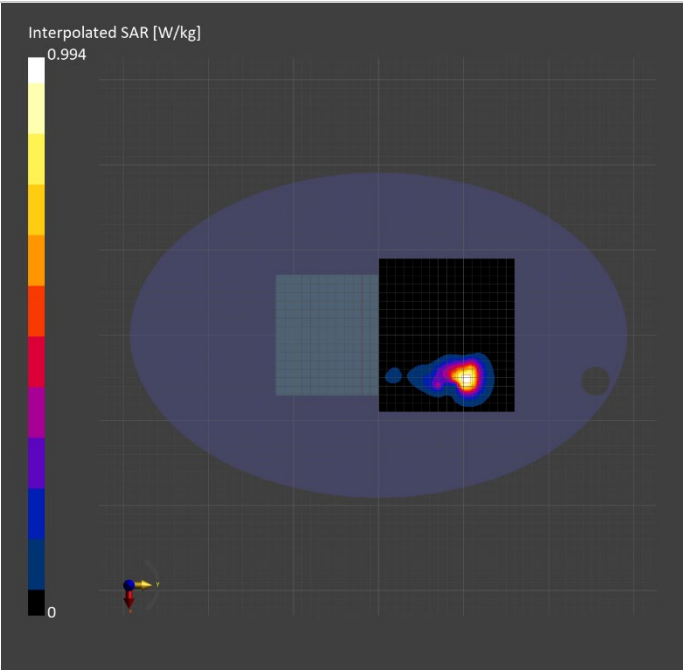
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL3500-2026-06-08	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 160.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-08	2026-06-08
psSAR1g [W/kg]	0.767	0.781
psSAR10g [W/kg]	0.348	0.346
Power Drift [dB]	-0.06	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.8
Dist 3dB Peak [mm]		9.0



P22 FR n66_QPSK30M_Rear Face_0cm_Ch353000_80RB_OS40

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n66	5G NR FR1 FDD, -	1765.000, 353000	7.46	1.41	40.4

Hardware Setup

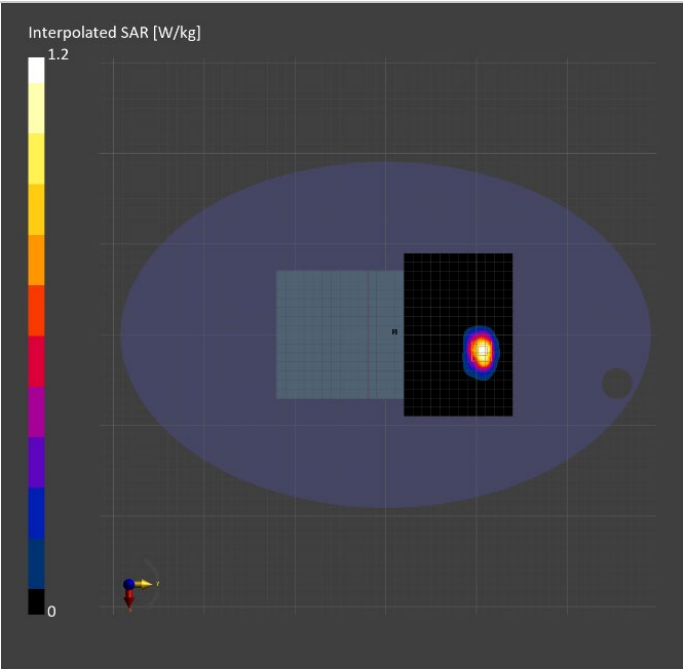
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL1750-2026-06-12	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-12	2026-06-12
psSAR1g [W/kg]	0.981	1.16
psSAR10g [W/kg]	0.514	0.568
Power Drift [dB]	0.14	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.9
Dist 3dB Peak [mm]		8.4



P23 FR n71_QPSK20M_Rear Face_0cm_Ch134600_1RB_OS1

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n71	5G NR FR1 FDD, -	673.000, 134600	5.14	0.882	43.1

Hardware Setup

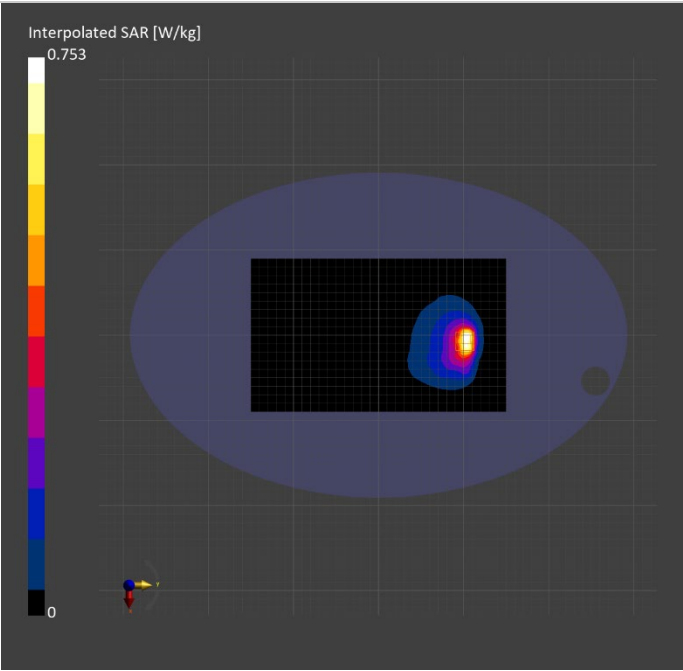
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL750-2026-05-22	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 300.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-05-22	2026-05-22
psSAR1g [W/kg]	0.626	0.625
psSAR10g [W/kg]	0.369	0.294
Power Drift [dB]	-0.11	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.3
Dist 3dB Peak [mm]		7.2



P24 FR n77_QPSK100M_Rear Face_0cm_Ch633334_270RB_OS0

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n77	5G NR FR1 TDD, -	3500.010, 633334	6.15	2.82	36.3

Hardware Setup

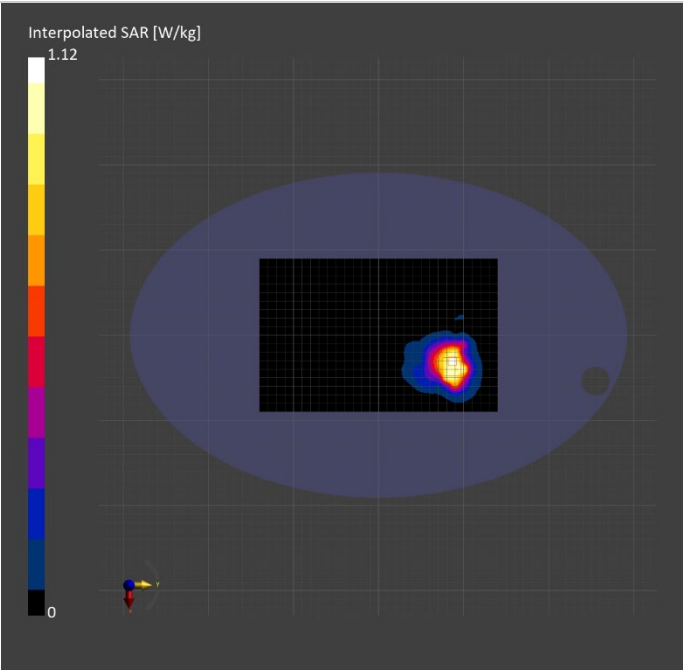
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL3500-2026-06-29	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-29	2026-06-29
psSAR1g [W/kg]	0.836	0.883
psSAR10g [W/kg]	0.424	0.443
Power Drift [dB]	-0.02	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		67.0
Dist 3dB Peak [mm]		9.0



P25 FR n78_QPSK100M_Rear Face_0cm_Ch633334_135RB_OS69

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Band n78	5G NR FR1 TDD, -	3500.010, 633334	6.15	2.82	36.3

Hardware Setup

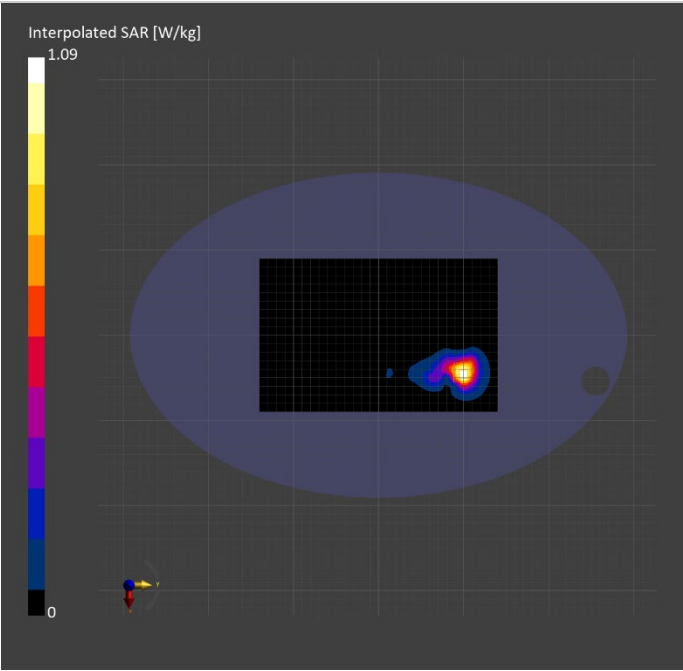
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL3500-2026-06-29	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-29	2026-06-29
psSAR1g [W/kg]	0.818	0.835
psSAR10g [W/kg]	0.366	0.368
Power Drift [dB]	-0.03	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.6
Dist 3dB Peak [mm]		8.5



P26 WLAN2.4G_802.11b_Rear Face_0cm_Ch6

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	WLAN 2.4GHz	WLAN, -	2437.000, 6	6.67	1.75	38.7

Hardware Setup

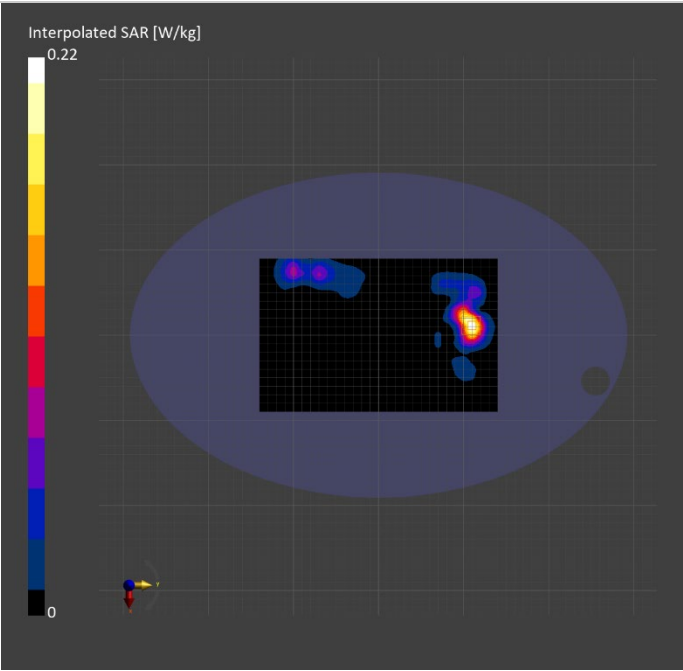
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2450-2026-06-02	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 280.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	N/A
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-02	2026-06-02
psSAR1g [W/kg]	0.170	0.169
psSAR10g [W/kg]	0.084	0.082
Power Drift [dB]	-0.06	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.5
Dist 3dB Peak [mm]		10.1



P27 WLAN5G_802.11ac-VHT40_Rear Face_0cm_Ch38

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	WLAN 5GHz	WLAN, -	5190.000, 38	5.35	4.50	37.4

Hardware Setup

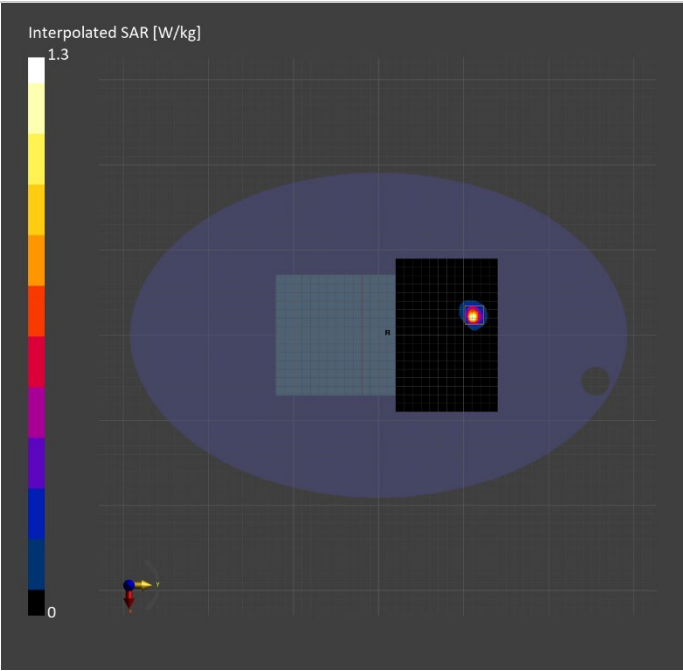
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL5250-2026-07-06	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-06	2026-07-06
psSAR1g [W/kg]	0.773	0.857
psSAR10g [W/kg]	0.214	0.234
Power Drift [dB]	0.05	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.9
Dist 3dB Peak [mm]		6.3



P28 WLAN5G_802.11ax-HE80_Rear Face_0cm_Ch58

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	WLAN 5GHz	WLAN, -	5290.000, 58	5.35	4.62	37.0

Hardware Setup

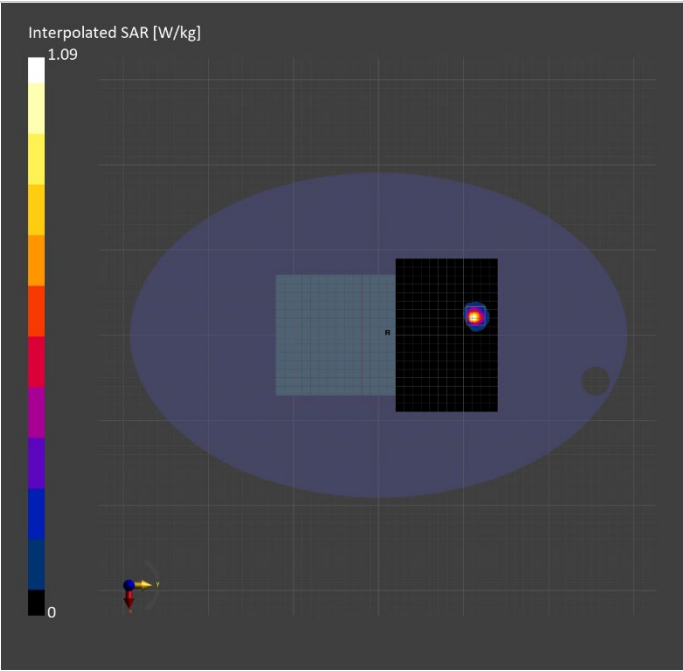
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL5250-2026-07-07	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1288, 2025-07-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-07	2026-07-07
psSAR1g [W/kg]	0.661	0.716
psSAR10g [W/kg]	0.183	0.192
Power Drift [dB]	0.12	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		60.8
Dist 3dB Peak [mm]		6.1



P29 WLAN5G_802.11ac-VHT80_Rear Face_0cm_Ch138

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	WLAN 5GHz	WLAN, -	5690.000, 138	4.93	5.06	36.5

Hardware Setup

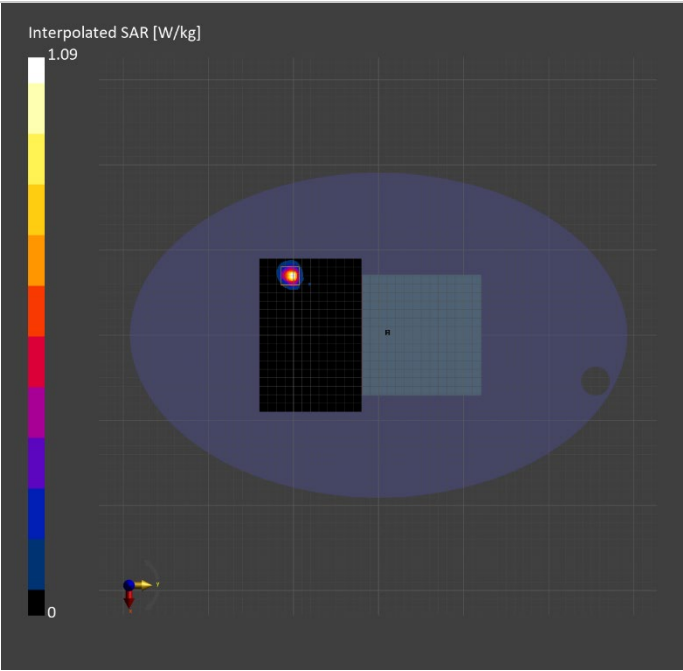
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL5600-2026-07-08	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1288, 2025-07-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-08	2026-07-08
psSAR1g [W/kg]	0.670	0.799
psSAR10g [W/kg]	0.185	0.211
Power Drift [dB]	0.02	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.8
Dist 3dB Peak [mm]		6.3



P30 WLAN5G_802.11n-HT40_Rear Face_0cm_Ch151

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	WLAN 5GHz	WLAN, -	5755.000, 151	5.02	5.11	36.3

Hardware Setup

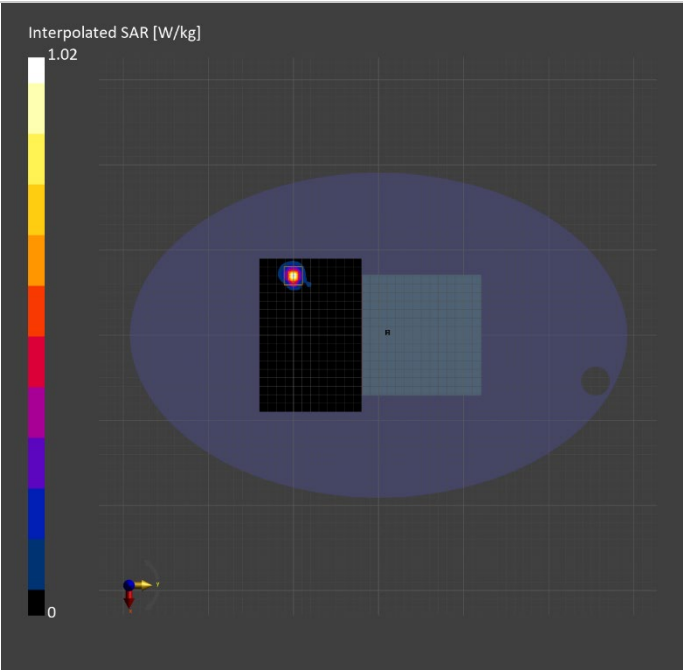
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL5750-2026-07-09	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1288, 2025-07-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-07-09	2026-07-09
psSAR1g [W/kg]	0.616	0.705
psSAR10g [W/kg]	0.164	0.188
Power Drift [dB]	-0.07	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		57.1
Dist 3dB Peak [mm]		6.5



P31 BT_GFSK_Rear Face_0cm_Ch39

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	6.67	1.75	38.6

Hardware Setup

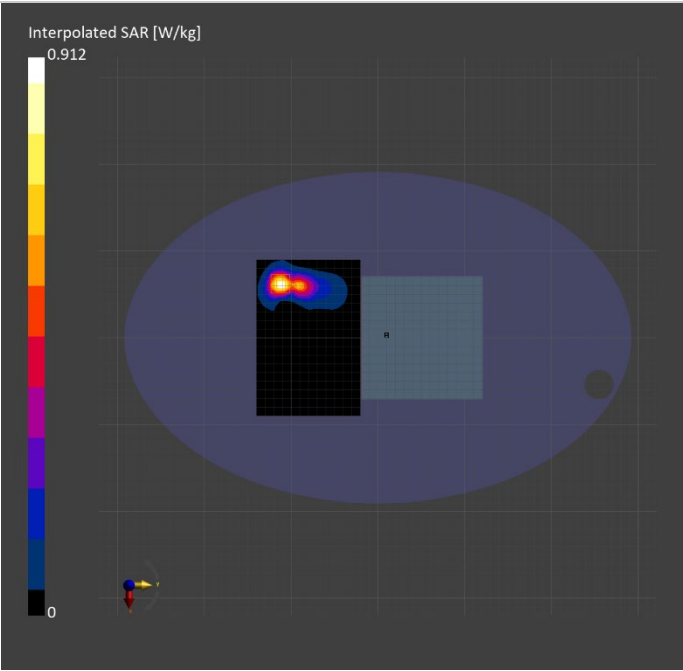
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL2450-2026-06-04	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-04	2026-06-04
psSAR1g [W/kg]	0.687	0.732
psSAR10g [W/kg]	0.316	0.325
Power Drift [dB]	-0.05	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.4
Dist 3dB Peak [mm]		10.8



P32 NFC_ASK_Rear Face_0cm

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	242.0 x 142.0 x 21.0		Tablet

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 0.00	Custom Band	-	13.560, -	16.7	0.717	53.2

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) - 2199	HSL13-2026-06-06	EX3DV4 - SN7802, 2025-07-21	DAE4 Sn1779, 2025-07-08

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	180.0 x 160.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2026-06-06	2026-06-06
psSAR1g [W/kg]	0.059	0.054
psSAR10g [W/kg]	0.041	0.022
Power Drift [dB]	-0.11	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.8
Dist 3dB Peak [mm]		6.2

